

**Notice of References Cited**

Application/Control No.

10/623,979

Applicant(s)/Patent Under  
Reexamination  
AOYAMA ET AL.

Examiner

Thang V. Tran

Art Unit

2653

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
<input checked="" type="checkbox"/>	A	US-6,700,842	03-2004	Nishi, Noriaki	369/124.12
<input checked="" type="checkbox"/>	B	US-6,377,525	04-2002	Iida, Michihiko	369/53.1
<input checked="" type="checkbox"/>	C	US-5,978,346	11-1999	Mizuno et al.	369/112.17
<input checked="" type="checkbox"/>	D	US-5,777,971	07-1998	Choi, Yang-Oh	369/44.23
<input checked="" type="checkbox"/>	E	US-5,535,055	07-1996	Ono et al.	359/495
<input checked="" type="checkbox"/>	F	US-5,124,868	06-1992	Matsubayashi et al.	369/110.04
<input checked="" type="checkbox"/>	G	US-5,119,352	06-1992	Bell, Jr., Bernard W.	369/13.29
<input checked="" type="checkbox"/>	H	US-5,060,212	10-1991	Fujita et al.	369/44.12
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
<input checked="" type="checkbox"/>	N	JP 11162033 A	06-1999	Japan	YONEZAWA et al.	--
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.